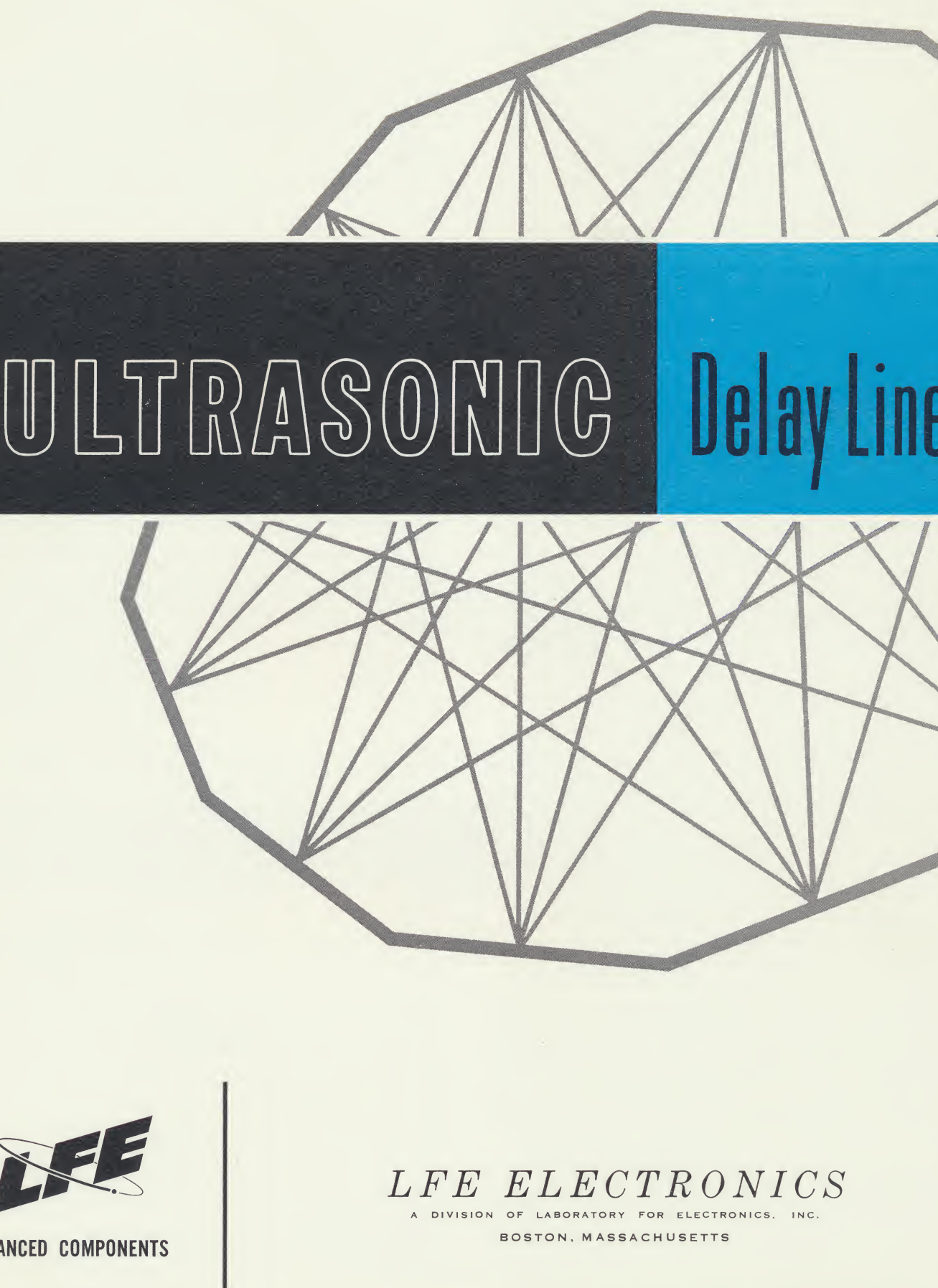




ULTRASONIC

Delay Lines



ADVANCED COMPONENTS

LFE ELECTRONICS

A DIVISION OF LABORATORY FOR ELECTRONICS, INC.

BOSTON, MASSACHUSETTS

Ultrasonic Delay Lines

Advances in radar technology have created a need for stable, reliable, wideband devices capable of achieving long delays with little distortion. Such devices are needed in MTI and distance measuring equipment, video integrators, and similar systems. Most of the necessary requirements can be fulfilled by ultrasonic delay lines, which make use of the slow velocities of acoustic waves through liquid or solid media to achieve long delays in relatively little space.

A typical ultrasonic delay line consists of an input transducer affixed to, or in contact with, the delay medium (see Figure 1). An electrical signal impressed upon this transducer (ordinarily a piezoelectric crystal or ceramic) is converted into an acoustic wave which is propagated through the

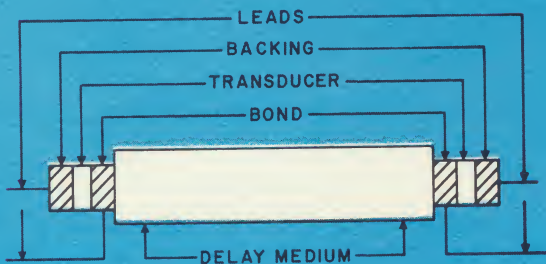


Figure 1. Ultrasonic Delay Line

medium with a velocity characteristic of that particular medium. Upon reaching the output transducer the acoustic signal is reconverted into a replica of the original electrical signal, delayed by a time interval equal to the propagation time through the delay medium. Of course, while it traverses the delay line, the signal undergoes attenuation and some distortion. While a great many delay media including water, mercury, nickel, and magnesium have been tried out over the years, present designs employ fused quartz almost exclusively: the use of metals is generally limited to aluminum and certain constant-modulus nickel alloys.

MATERIALS

Fused quartz, or vitreous silica, combines excellent loss properties over a wide frequency range with good handling and manufacturing characteristics, and provides a good impedance match with commonly used transducer materials. Like all solids, it can sustain both of the major modes of propagation of ultrasonic waves: the longitudinal, or compressional mode, in which the particle motion is in the same direction as the wave motion; and the shear mode, in which the particle motion is perpendicular to the direction of travel of the acoustic wave. The former mode is generated by X-cut quartz crystals, and in fused quartz travels with a velocity of approximately 4.26 microseconds per inch; shear waves are generated by Y-cut or AC-cut crystals, and travel with a velocity of approximately 6.75 microseconds per inch. Both types of waves can be generated by suitably polarized piezoelectric ceramics such as barium titanate and lead zirconate titanate (PZT). Because of the high temperature coefficient of quartz (-70 to -80 ppm/ $^{\circ}\text{C}$ for shear waves, -100 ppm/ $^{\circ}\text{C}$ for compressional waves), close control of the delay requires that the delay line be packaged in an isothermal enclosure which is generally maintained above the maximum ambient temperature of the device. Added benefits of high temperature operation are an increase in bandwidth and a decrease in attenuation.

To eliminate the restrictions imposed by the high temperature coefficient of delay of quartz, various glass compositions exhibiting low temperature coefficients have been developed. The delay stability of the zero-temperature coefficient glass used by LFE is illustrated in Figure 2. Acoustic losses are somewhat greater than in fused quartz, so that the use of zero-temperature-coefficient glass is limited to applications requiring delays under 300 microseconds; however, this disadvantage is more than offset by the better bandwidth and spurious characteristics achievable with glass.

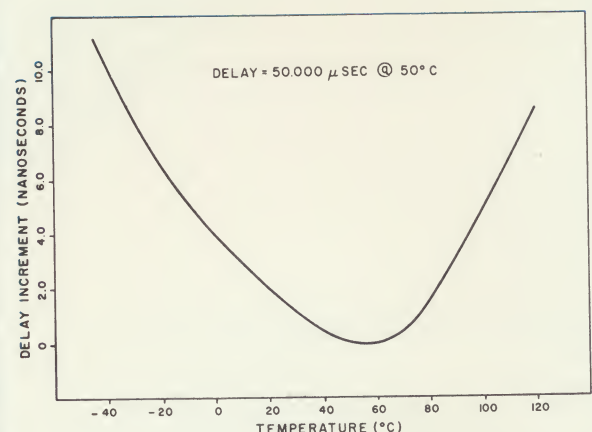


Figure 2. Delay vs. Temperature Characteristics — Zero-Temperature-Coefficient Glass Delay Lines

ic Delay Lines...

CONFIGURATIONS

It is obvious that for long path lengths a straight bar configuration would be both impractical and costly; hence, for long delays the beam path is folded, and the ultrasonic beam is reflected from plane facets machined on the delay line blank (Figure 3). In such lines the thickness shear mode (with particle motion perpendicular to the major faces of the blank) is generally used to take advantage of the slower acoustic velocity per unit length, and to reduce spurious signals. To a great extent the limits of the state-of-the-art are set by the compromise between compactness of the delay line blank (or in other words, by the number of folds in the delay path) and the achievable minimum spurious signal level; at LFE, polygon configurations are optimized with the aid of a high speed digital computer. New patterns are constantly being devised, and nearly two hundred are presently filed. Long delays are available (up to 6000 microseconds in a single 18-inch blank), and of course longer delay times may be obtained by combination. A number of novel configurations — including a patented three-dimensional path device — have been developed in this laboratory.

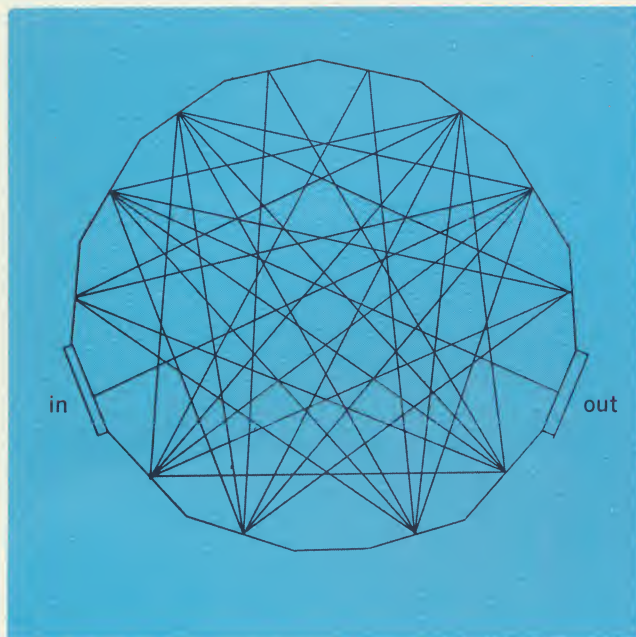


Figure 3. Typical Folded Path Configuration — 15MS31

TRANSDUCERS

A critical step in the manufacture of solid ultrasonic delay lines is the design of the transducer assembly. Various proprietary methods have been evolved to ensure good impedance match between the transducer and the solid medium so as to achieve maximum signal transfer with minimum spurious signals and distortion. These electrical features must be coupled with stable mechanical characteristics to permit operation over environmental extremes. To prevent unwanted echoes from the transducer-air interface, and to increase bandwidth, an acoustic absorber is mounted behind each transducer; the proper selection and configuration of these absorbers are important considerations in the design of a specific delay line.

Since the transducers are resonant devices, a solid ultrasonic delay line behaves like a bandpass filter with a frequency of minimum attenuation near the resonant frequency of the transducers. To derive maximum benefit from this property, the signal to be delayed or stored is generally used to modulate an RF carrier whose frequency is in the vicinity of the center frequency of the delay line; the delayed, modulated RF signal is detected to recover the original information (see figure 4). It is also possible to operate ultrasonic delay lines with RF carrier frequencies which are odd harmonics of the center frequency. Fundamental carrier frequencies range from 500 Kc to over 100 Mc; the use of harmonic carriers permits operation up to 500 Mc.

Under certain conditions it is possible to delay unmodulated signals; delay lines designed for this purpose are described in our Digital Delay Line brochure.

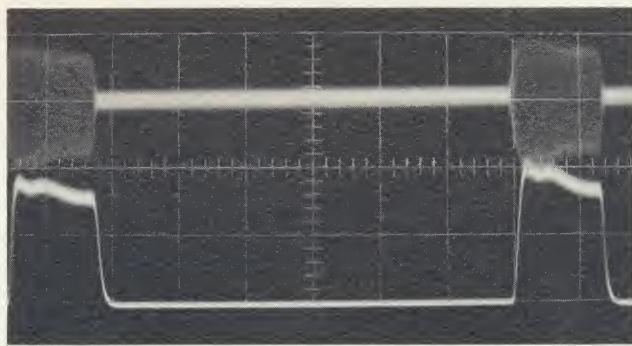


Figure 4. Typical Ultrasonic Delay Line Waveforms. Upper Trace: Undelayed Modulated RF Signal. Lower Trace: Delayed, Detected Signal

TRANSDUCER EQUIVALENT CIRCUIT

A simplified equivalent circuit of a solid delay line transducer is shown in Figure 5. L_O is an external inductor designed to resonate with C_O , the shunt capacitance of the transducer, at the delay line center frequency. L_I and C_C are the equivalent series mechanical reactances of the transducer and correspond to inertia and compliance, respectively. R_A is the so-called radiation resistance and may be regarded as the characteristic impedance of the line; R_L is the load resistance of the transducer.

Values of C_O ordinarily range from 5 to 200 picofarads for quartz crystal transducers, and up to several thousand picofarads for ceramic transducers. Typical values of R_A for quartz transducers range from 1000 ohms to about 10,000 ohms; for ceramic transducers R_A values may be as low as 5 ohms.

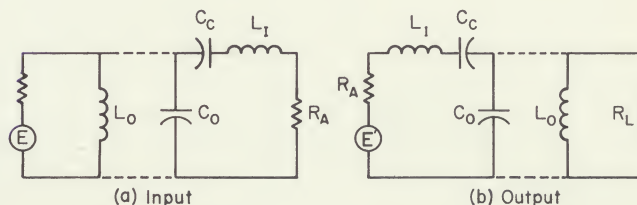


Figure 5. Delay Line Transducer Equivalent Circuit

DEFINITIONS

In order to assist the user in setting up specifications and test methods for ultrasonic delay lines, the following definitions of important parameters are provided.

Carrier Frequency

The RF carrier which is modulated by the information to be delayed, and which may or may not coincide with the peak frequency of the delay line.

Time Delay

The time interval between input and output information, generally the measured interval between the input signal and the delayed output signal.

Bandwidth

a) Acoustic Bandwidth — The acoustic bandwidth defines the basic performance characteristics of the line without the effects introduced by extraneous circuit elements. It is generally measured by resonating the transducers at each frequency with an inductor and taking the half power (3 db) points of the resulting response curve, or reading with low resistance loads.

b) Electrical Bandwidth — This is an operational term which describes the performance of a delay line under actual operating conditions. It is the 3 db bandwidth of the delay line terminated in the exact manner in which it will be used in the circuit; in this case the transducer capacity and its effect on the total circuit must be considered. Clearly the electrical bandwidth can never be quite as wide as the acoustic bandwidth without external compensation. The differences in acoustic and electrical bandwidths for a typical ultrasonic delay line are illustrated in Figure 6.

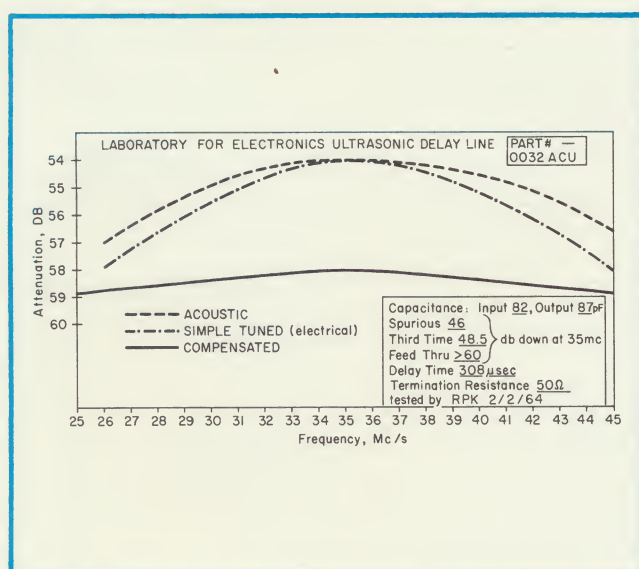


Figure 6. Acoustic and Electrical Bandwidth Characteristics

Spurious Signals

Undesired signals which appear at the delay line output may originate from any of a variety of causes; maximum permissible levels (peak values) for each type are generally specified separately. Types of spurious signals are:

a) Feedthrough — This type of spurious signal is caused by capacitive coupling between input and output terminals, resulting in the appearance of undelayed noise. Such parasitic signals can be suppressed by careful terminal placement and good shielding, both during manufacture and during installation.

b) Triple Travel — This type of spurious signal occurs after a time interval equal to three times the line delay; it is due to acoustic mismatch at the transducers permitting part of the output signal to be reflected back to the input transducer, and back again to the output. These undesirable signals are minimized by proper transducer and backing design.

c) Random Spurious Signals — Other types of spurious signals are caused by beam spreading or diffraction, mode conversion, and non-homogeneity of the delay medium. These signals are minimized by selecting the optimum configuration; by judicious placement of acoustic corner absorbers; by proper selection of transducer geometry; by close control of angular tolerance; and by selection and grading of the delay line blanks.

Attenuation

Attenuation or insertion loss in an ultrasonic delay line is the comparison of output voltage to input voltage under specified load conditions. In a short quartz delay line most of the signal loss is due to the transducers, the medium itself being essentially absorption-free. In glass delay lines, or in long quartz lines, the medium contributes substantially to the overall loss.

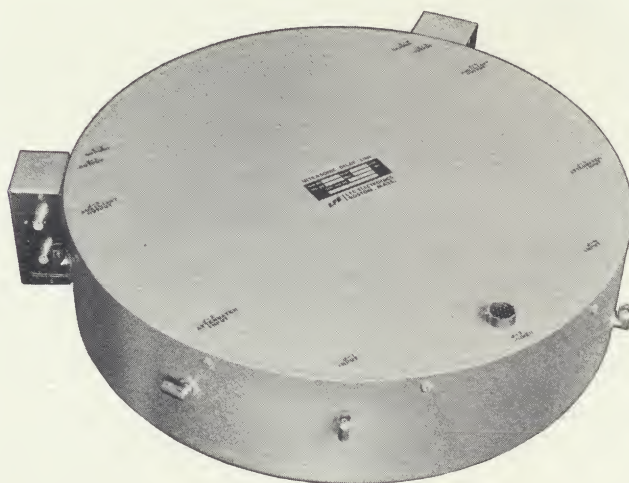


Figure 7. Four-channel Heated Delay Line

Delay per Channel: 3300 μ sec, Center Frequency: 30 Mc
Application: MTI System

Delay Lines...

MEASUREMENTS

Basic ultrasonic delay line measurement set-ups are presented in Figure 8. Attenuation measurements are made by a comparison method, with a variable attenuator substituted for the delay line. Spurious ratio is found by lowering the input level with the series attenuator until the delayed signal is at the spurious level. Bandwidth measurements are carried out by sweeping the RF oscillator over the desired frequency range and recording output levels at each frequency; or by using the set-up shown in Figure 8b.

Delay measurements may be carried out in two ways:

- If the pulse repetition rate is fixed, the delay between input and output pulses may be compared against a time standard.
- If the PRF is adjustable, it is varied until input and output pulses coincide; the delay is then some integral function of the driving PRF.

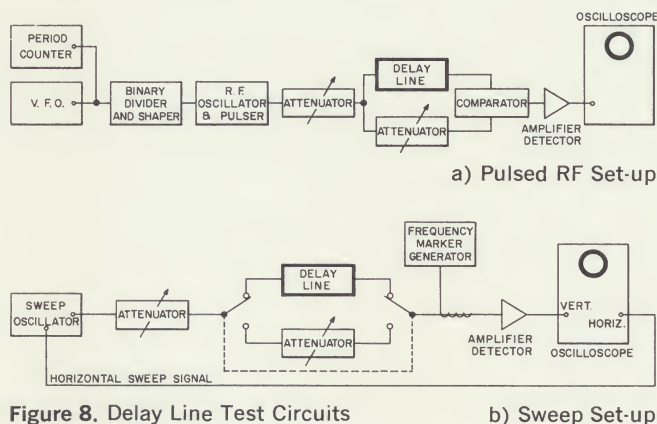


Figure 8. Delay Line Test Circuits

b) Sweep Set-up

ECHO LINES

A special class of ultrasonic delay lines is used to generate trains of pulses separated by equal and precise time intervals. Such lines — known as echo lines or rangemarkers — generally consist of a straight fused or crystalline quartz bar, either with a single transducer, or with a transducer at each end.

In the so-called single-ended echo line, an impulse fed into the transducer is reflected back and forth between the two ends of the bar. Each time the acoustic signal impinges upon the transducer an electrical signal is generated; the pulse spacing is therefore twice the propagation time through the bar. In the double-ended type, the first pulse occurs after the input pulse has traversed the bar once; the spacing between subsequent pulses is again twice the propagation time through the bar. To reduce absorption of the echoes the transducer backing is generally left off. The typical pulse train generated by an echo line is illustrated in Figure 9. LFE has manufactured echo lines with center frequencies up to 425 Mc.

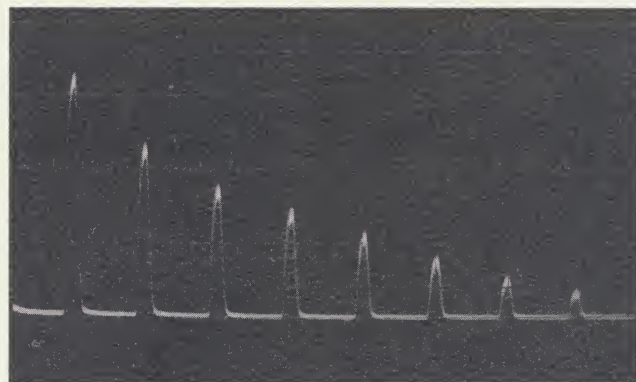


Figure 9. Echo Line Pulse Train

CHARACTERISTICS OF TYPICAL LFE ULTRASONIC DELAY LINES

LFE Part Number	Delay	Delay Medium	Center Frequency	Bandwidth		Spurious			Attenuation	Transducer Capacity	Case Size
				Acoustic	Electrical	Feed-through	Triple Travel	Random			
0023 ACU	0.5-12.0 μ s	0 TC Glass	30 Mc	24 Mc min	14 Mc into 75 Ω	>60 db	>35 db	>60 db	40 db into 75 Ω	60 pf	$\frac{3}{4}$ " x $\frac{3}{4}$ " x $1\frac{1}{4}$ "
0046 ACU	50 μ s	0 TC Glass	60 Mc	35 Mc min	20 Mc into 75 Ω	>50 db	45 db	>60 db	54 db into 75 Ω	60 pf	$3\frac{1}{2}$ " x 2" x 1"
100(3)	2500 μ s	Fused Quartz	30 Mc	18 Mc	12 Mc into 75 Ω	>60 db	>60 db	55 db	59 db into 75 Ω	65 pf	$14\frac{1}{2}$ " d x $1\frac{1}{2}$ "
0032 ACU	300 μ s	Fused Quartz	35 Mc	12 Mc to -1 db points	21 Mc to -1 db points *	>50 db	>50 db	47 db	58 db into 50 Ω	0 $\ddagger$	7" d x $1\frac{1}{4}$ "
57357	545 μ s	Fused Quartz	9 Mc	3-4 Mc	3.5 Mc into 100 Ω	>60 db	35 db	44 db	53 db into 100 Ω	35 pf	$5\frac{7}{8}$ " d x $\frac{3}{4}$ "
0020 ACU	400 μ s	Fused Quartz	60 Mc	35 Mc	24 Mc into 50 Ω	>60 db	53 db	>60 db	53 db into 50 Ω	90 pf	$6\frac{1}{2}$ " d x $1\frac{1}{4}$ "
0041 ACU	83 μ s	Fused Quartz	75 Mc	>35 Mc	16 Mc to -1 db points	60 db	53 db	>60 db	50 db into 50 Ω	70 pf	$5\frac{3}{4}$ " d x $2\frac{3}{4}$ "

*Electrically compensated at the transducers

$\ddagger$ Tuned out at 35 Mc



Figure 10. Tapped Glass Delay Line Package
 Delay per Tap: $0.500 \pm 0.010 \mu\text{sec}$, Center Frequency: 30 Mc
 Application: Coherent Radar System

SPECIFYING ULTRASONIC DELAY LINES

Since both electrical and mechanical requirements vary widely, ultrasonic delay lines can rarely be procured from stock. Specifications for custom-designed components should include the following information:

1. Total delay and tolerance
2. Nominal center frequency
3. Minimum allowable bandwidth
4. Maximum allowable attenuation
5. Maximum permissible spurious signal levels
6. Input and output impedances
7. Load resistance
8. Operating temperature range, and stability within that range. In the event that quartz is to be used as the delay medium, state power available for heaters, expected ambient levels, and allowable warm-up time.
9. Physical size, packaging, and type of connectors
10. Environmental requirements
11. A general description of the application, with schematics of driving, detecting and amplifying circuits, is desirable. Input signal characteristics should accompany the specifications.

Echo line specifications should include the following information:

1. Single or double-ended type
2. Input pulse width
3. Required number of echoes over a given time period, or pulse spacing
4. Echo decay rate

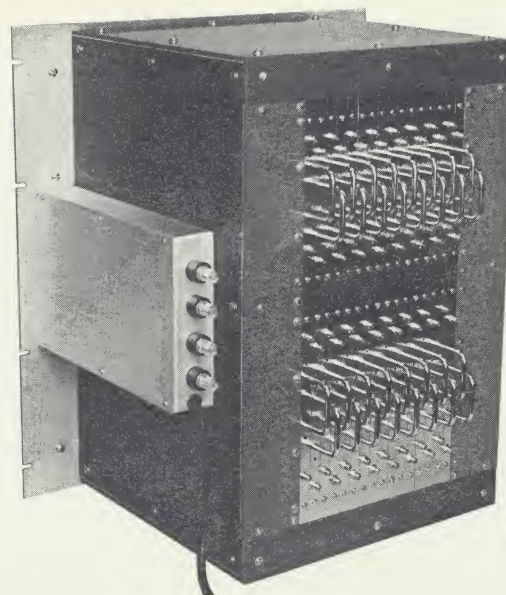


Figure 11. Modular Multidelay Package With Isothermal Enclosure.
 No. of Delay Lines: 32, Delay Tolerance: ± 8 nanoseconds
 Center Frequency: 60 Mc, Temperature Stability: 0.01°C
 Application: Coherent Radar System

SPECIAL UNITS

In addition to the conventional delay lines described above, LFE Electronics offers delay or memory packages for special requirements. These include:

- Tapped Delay Lines
- Stacked Delay Lines
- Variable Delay Lines
- Multiple-channel Delay Lines
- Isothermal Quartz Delay Line Packages Incorporating Heaters and Associated Control Circuitry
- Multipackages incorporating two or more delay lines
- Complete serial memory systems

Some representative designs are illustrated in the accompanying photographs.

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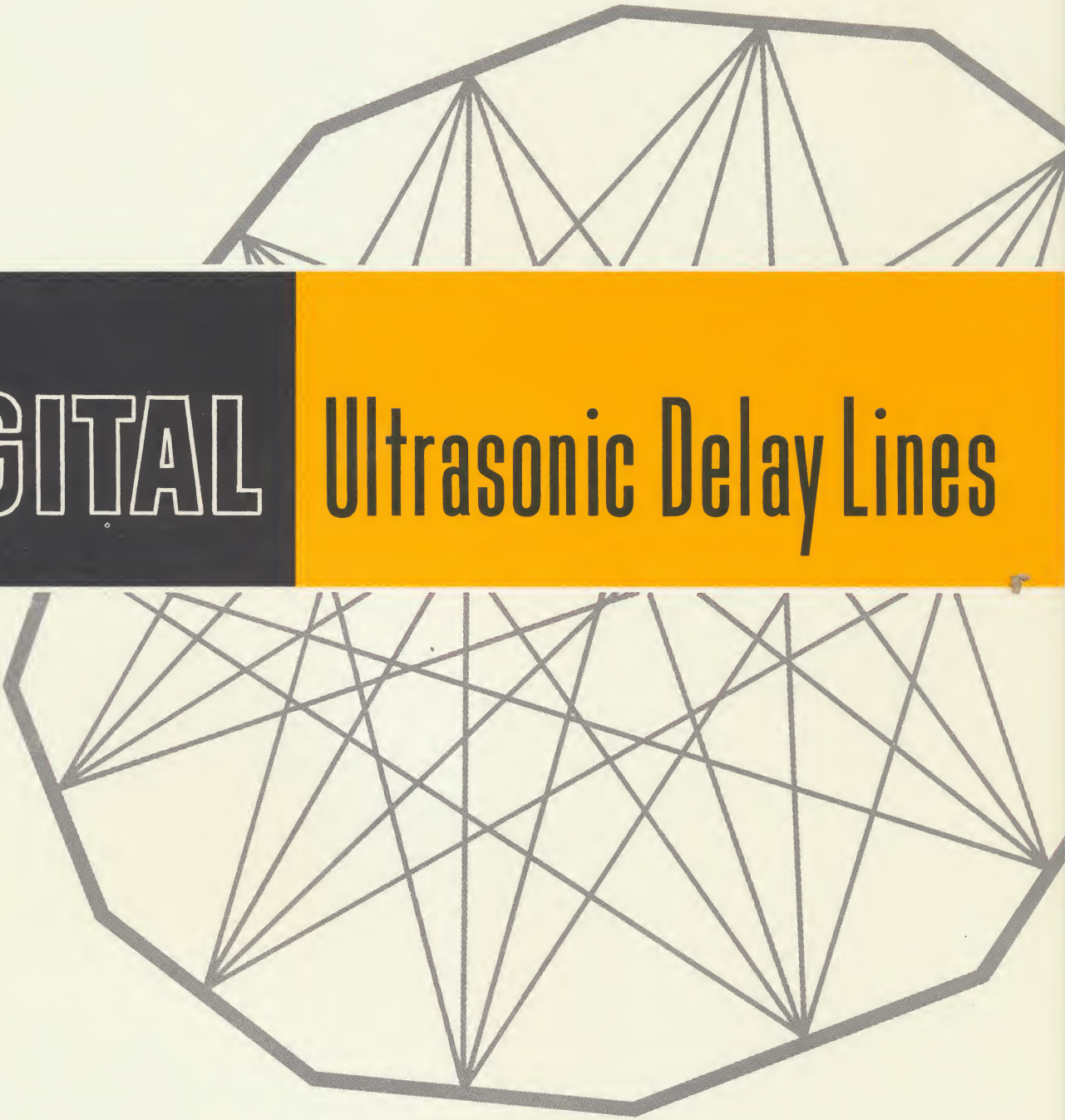
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A DIVISION OF LABORATORY FOR ELECTRONICS, INC.

1075 COMMONWEALTH AVENUE • BOSTON, MASSACHUSETTS

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Delay Lines • Filters • Transformers • Memory Systems
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DIGITAL

Ultrasonic Delay Lines



ADVANCED COMPONENTS

LFE ELECTRONICS

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BOSTON, MASSACHUSETTS

EVOLUTION OF THE DIGITAL ULTRASONIC DELAY LINE

With the advent of present-day, high-speed miniaturized computer circuitry, many conventional serial memory devices — such as magnetic drums, tapes and discs, and magnetostrictive delay lines — have been rendered almost obsolete. In effect, the search for memory devices compatible with such circuitry has resulted in the development of a new family of solid-state delay devices, based on conventional ultrasonic delay line technology — Digital Ultrasonic Delay Lines. Unlike conventional ultrasonic delay lines, these devices are designed to:

- Operate without an RF carrier;
- Handle digital data in the form of video pulses, and;
- Provide minimum distortion and loss.

Bit rates from 0.5 to 40 megacycles, with storage capacities well in excess of 20,000 bits, are presently achievable. The basic theory and processes involved in the design of digital delay lines, as well as typical parameters, applications, test methods and specification procedures, are outlined in the following paragraphs.

SOLID ULTRASONIC DELAY LINES

Ultrasonic delay lines make use of the relatively slow velocity of acoustic waves through dense solid media to achieve long delays in relatively small space. The electrical signals to be delayed are converted into acoustic waves by the input transducer affixed to the delay medium (see Figure 1). Upon reaching the output transducer, the acoustic signal is reconverted into an electrical signal delayed by a time interval equal to the propagation time through the delay medium. To conserve space and material, the acoustic beam path may be folded one or several times, as shown in Figure 2. Since the transducers are resonant devices, a solid delay line acts as a bandpass network with a frequency of minimum attenuation in the vicinity of the transducers' resonant frequency.

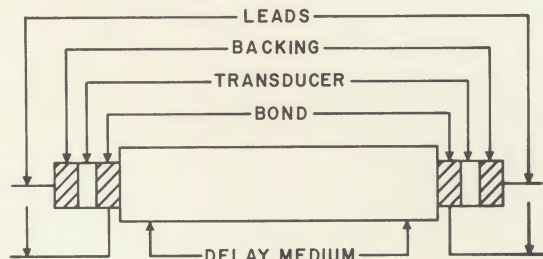


Figure 1. Solid Ultrasonic Delay Line

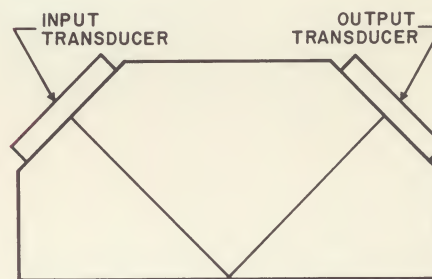


Figure 2. Ultrasonic Delay Line with Folded Acoustic Path

Digital vs. Conventional Delay Lines

In conventional ultrasonic delay lines, the information to be delayed modulates an RF carrier whose frequency is equal to the center frequency of the delay line; the delayed signal is then amplified and detected. This scheme permits operation of the delay line in its most efficient mode, and does not impose strict limits upon bandwidth and dispersion requirements.

If a video pulse is applied to a conventional ultrasonic delay line, its frequency components are essentially analyzed in the time domain, with the higher frequency components delayed less and arriving first (Figure 3); the resulting pulse is highly distorted. Digital delay lines, however, are corrected for this type of distortion, with the result that a delayed video pulse approximates the typical pulse response of the ideal bandpass filter with linear phase shift (see Figure 4). For a delay line with a given center frequency, the optimal video pulse width should be equal to approximately one-half the period of the center frequency. If the line is operating in an RZ mode, the pulse spacing is equal to the pulse width, and the maximum bit rate of the line is equal to the nominal center frequency.

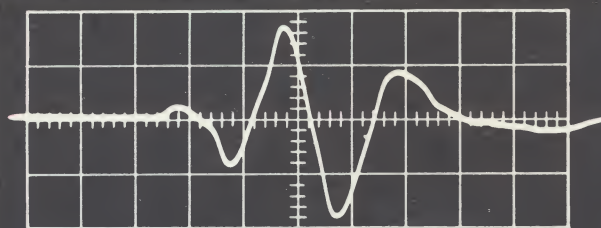


Figure 3. Dispersion in Acoustic Delay Line

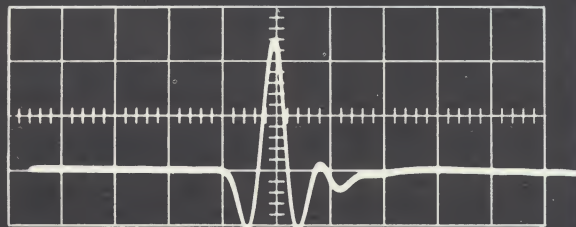


Figure 4. Output Pulse, Non-Dispersive Acoustic Delay Line

Glass vs. Quartz Medium

Until recently, the standard medium for ultrasonic delay lines has been fused quartz, which combines excellent loss properties over a wide frequency range with good handling and manufacturing characteristics, and which provides a good impedance match with commonly used transducer materials. The major disadvantage of quartz, however, lies in its high temperature coefficient (-70 to -80 ppm/ $^{\circ}\text{C}$). Various glass compositions exhibiting low temperature coefficient and adequate loss characteristics have been developed for use in digital delay lines. These glasses have a temperature coefficient of zero at one specific temperature within the 20 to 50°C range, and a linear change in temperature coefficient on either side of this minimum. Figure 5 illustrates the temperature characteristics of the zero-temperature-coefficient glass used by the Advanced Components Operation of LFE Electronics in the manufacture of digital delay lines.

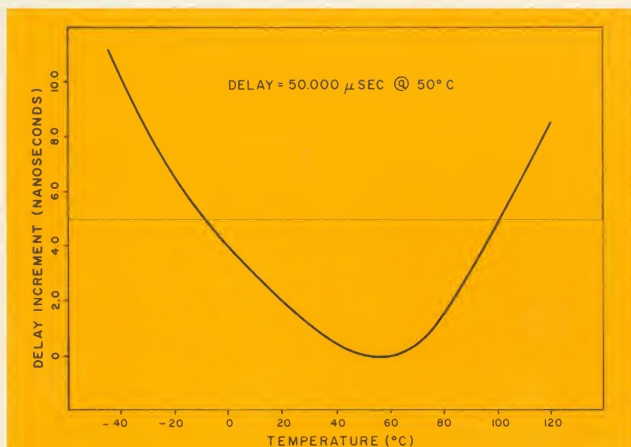


Figure 5. Delay vs. Temperature Characteristics — Zero-Temperature-Coefficient Glass Delay Lines

Besides eliminating the need for close temperature control in most applications, zero-temperature-coefficient glass exhibits an acoustic impedance which closely matches that of quartz transducers. This characteristic yields wide bandwidths and minimizes transducer ringing, which is a major source of distortion. Acoustic losses are somewhat greater than in fused quartz, with the result that the use of zero-temperature-coefficient glass is restricted to relatively short delay lines.

Transducer materials used in solid digital delay lines fall into two categories — crystalline quartz and piezoelectric ceramics. Quartz crystals are relatively low efficiency devices (coupling coefficient = 0.14) with resultant high radiation resistances; since the quartz crystal is essentially a constant current device, changing the load resistance will change the output voltage level. The low dielectric constant of quartz yields low transducer capacities even at very high frequencies. Piezoelectric ceramics, such as barium titanate, lead zirconate titanate (PZT), or lead metaniobate, are characterized by high coupling coefficients (0.7 and above) which result in low radiation resistances. Their very high dielectric constants prevent their application to high frequency delay lines unless special techniques are made use of to limit transducer capacitance.

DEFINITIONS AND MEASUREMENTS

Most parameters of concern in digital lines — such as capacity and attenuation — are conventional and require no special definitions; however, special characteristics require some elaboration. The waveforms presented below (Figures 6 and 7) illustrate some of these characteristics. Figure 8 outlines a typical test setup for measuring delay, attenuation, and spurious levels.

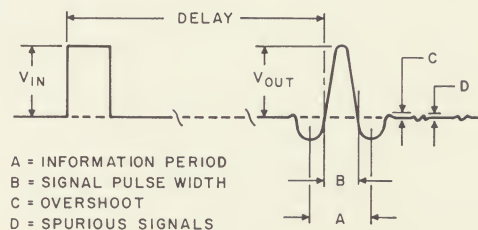


Figure 6. Waveform Definitions — RZ Mode

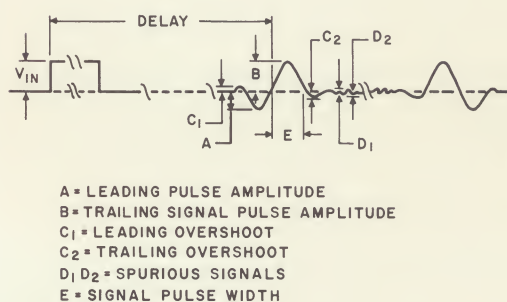


Figure 7. Waveform Definitions — NRZ Mode

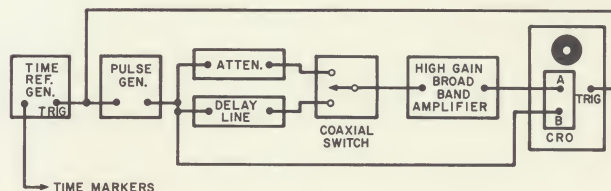


Figure 8. Typical Test Setup for Digital Delay Lines

APPLICATIONS

In the field of data processing, digital ultrasonic delay lines have found wide application as serial memory elements for bulk and buffer storage, as scratch-pad memories, shift registers and trigger delay devices, or for pulse-shaping purposes. The high storage capabilities, mechanical ruggedness, and electrical and chemical stability of digital ultrasonic delay lines also suggest their utilization in many space, missile and communication applications.

A typical recirculating memory system employing a digital ultrasonic delay line is illustrated in Figure 9.

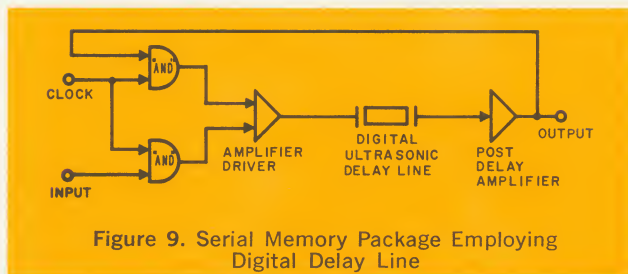


Figure 9. Serial Memory Package Employing Digital Delay Line

GENERAL CHARACTERISTICS OF DIGITAL DELAY LINES

	Quartz-Quartz	Ceramic-Quartz	Quartz-Glass	Ceramic-Glass
Delay Range	1-1000 μ sec	1-1000 μ sec	1-150 μ sec	1-150 μ sec
Bit Rate or Center Frequency Range	5-40 Mc	3-25 Mc	5-40 Mc	0.5-25 Mc
Bit Length Range	10-100 nsec	20-150 nsec	10-100 nsec	20-1200 nsec
Transducer Capacity Range	25-150 pF	50-10,000 pF	25-150 pF	50-10,000 pF
Attenuation Range	40-80 db into 50 ohms	20-60 db into 50 ohms	30-80 db into 50 ohms	20-80 db into 50 ohms
Typical Signal/Noise Ratio	10-20/1	10-20/1	15-25/1	5-15/1
Temperature Coefficient of Delay	-75ppm/ $^{\circ}$ C $\pm$ 5ppm/ $^{\circ}$ C	-75ppm/ $^{\circ}$ C $\pm$ 5ppm/ $^{\circ}$ C	See Fig. 5	See Fig. 5
Radiation Resistance (Typical)	500-10,000 ohms	1-200 ohms	2000-8000 ohms	1-200 ohms

Note: Digital delay lines are generally encased in metal cans, both for shielding purposes and for mechanical stability. Packages designed for hostile environments or to military specifications can also be provided. A variety of painted or plated finishes are available.

SPECIFYING DIGITAL DELAY LINES

Specifications should include the following:

- (1) Total delay, or total storage capacity, and tolerances
- (2) Maximum bit rate
- (3) Mode of operation (RZ or NRZ)
- (4) Video pulse or bit characteristics: width, amplitude, rise and fall times, etc.
- (5) Signal-to-noise ratio
- (6) Input and output admittances
- (7) Load resistance
- (8) Pulse attenuation
- (9) Operating temperature range, and stability within that range; in the event that quartz is to be used as the delay medium, state power available for heaters and expected ambient levels
- (10) Physical size, packaging, and type of connectors
- (11) Environmental requirements

A general description of the application, with schematics of driving and amplifying circuitry, is also useful.

SPECIAL DIGITAL UNITS

In addition to the conventional digital delay lines described above, the Advanced Components Operation of LFE Electronics offers delay or memory packages for special requirements.

These include:

- Tapped delay lines
- Digital echo lines
- Multiple-channel delay lines
- Adjustable delay lines
- Isothermal quartz delay line packages, incorporating heaters and associated control circuits
- Multipackages incorporating two or more delay lines
- Complete serial memory systems

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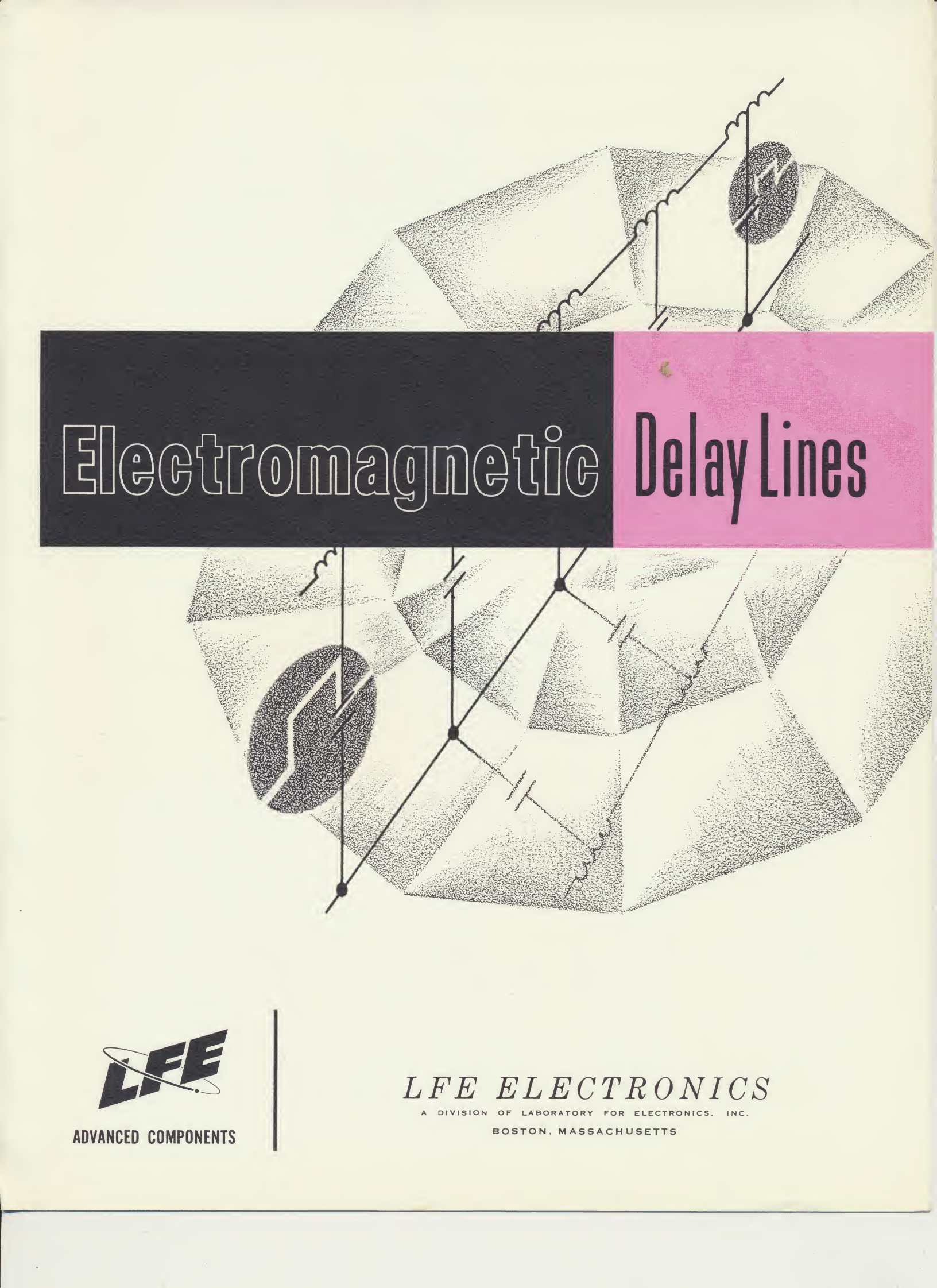
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Electromagnetic Delay Lines



ADVANCED COMPONENTS

LFE ELECTRONICS

A DIVISION OF LABORATORY FOR ELECTRONICS, INC.

BOSTON, MASSACHUSETTS

Introduction

Electromagnetic delay lines are passive filter networks comprised of capacitive and inductive elements with properties such that a signal impressed upon the input will issue from the output after a specific time interval, the magnitude of which is a function of the L and C components of the line. Since in practice the elements of a delay line are not ideal, the signal undergoes attenuation and distortion as it passes through the line.

While a delay line may be of any one of the various types of filters — low-pass, bandpass, or high-pass — most commonly used delay lines are of the low-pass, ladder type. These in turn are divided into two major categories: lumped-parameter and distributed-parameter networks. In the former, the inductive and capacitive elements are discrete, separate components. In the latter, a single element — generally a solenoid wound over a conductive core — combines the desired properties of inductance and capacitance. In general, lumped-parameter delay lines are superior to distributed-parameter networks with respect to most characteristics, such as the maximum achievable quality factor (delay-to-rise time ratio); attenuation; delay and impedance range; and size and packaging flexibility. Distributed-parameter delay lines nor-

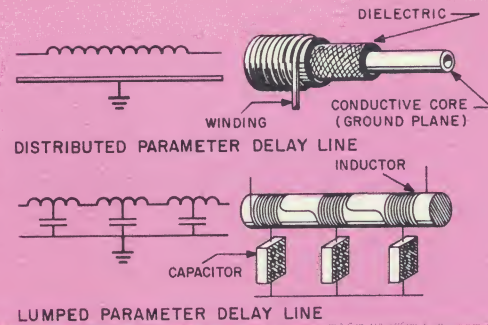


Figure 1A

mally exhibit excellent spurious response, and are quite attractive in many applications because of their low cost. Among their chief disadvantages are their high attenuation, their poor temperature stability, and their restrictive form factor.

The following paragraphs, covering definitions and measurements for electromagnetic delay lines, apply equally to both types.

DEFINITIONS FOR ELECTROMAGNETIC DELAY LINES

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3. DEFINITIONS AND SYMBOLS

3.1 Distortion — May be defined specifically as a special case or more commonly as a generalized or all encompassing condition.

3.1.1 Specific — Defined in % by specifically indicating the maximum value of pre-pulse distortion (b), pulse amplitude distortion (c), and post pulse distortion (d) relative to the pulse amplitude (E), where each is not necessarily of equally permissible amplitude. May further be defined by indicating the period in which these spurious responses may occur.

3.1.1.1 PRE-PULSE DISTORTIONb (%)

$$b(\%) = \pm \frac{|b|}{E} \times 100$$

where |b| represents peak pre-pulse distortion.

3.1.1.2 PULSE AMPLITUDE DISTORTIONc (%)

$$c(\%) = \pm \frac{|c|}{E} \times 100$$

where |c| represents peak pulse amplitude distortion.

3.1.1.3 POST PULSE DISTORTIONd (%)

$$d(\%) = \pm \frac{|d|}{E} \times 100$$

where |d| represents peak post pulse distortion.

3.1.2 All EncompassingS (%)

Defined as the largest peak amplitude of all spurious responses either in the positive or negative direction relative to the pulse amplitude. Calculated in %.

$$S(\%) = \pm \frac{|b| \text{ or } |c| \text{ or } |d|}{E} \times 100$$

where |b|, |c| or |d| represents largest peak amplitudes.

3.2 Impedance

3.2.1 Characteristic ImpedanceZ₀
That value of terminating impedance which provides minimum reflections to the input of the line.

3.2.2 Source ImpedanceZ_s
The impedance of the pulse source as seen by the delay line input terminals.

3.2.3 Terminating ImpedanceZ
The impedance of the load as seen by the delay line output terminals.

3.3 Pulse Amplitude (see figures)E

3.4 Temperature Coefficient of DelayT_c
The change in delay with temperature expressed as:

3.4.1 Parts per million per degree centigrade(PPM/°C)

or,

3.4.2 Microsecond per microsecond per degree centigrade (μsec/μsec/°C)

or,

3.4.3 Percent per degree centigrade(%/°C)

3.5 Tilth

Expressed in % as:h (%)

$$h(\%) = \pm \frac{|h|}{E} \times 100$$

where |h| is absolute value of height of tilt axis.

3.6 Time

3.6.1 Delay Line Fall Timet_f

The time of the amplitude decreasing edge of the output pulse, assuming a step-function input.

3.6.2 Delay Line Rise Timet_r

The time of the amplitude increasing edge of the output pulse, assuming a step-function input.

3.6.3 Delay Timet_d

Elapsed time between the 50% amplitude of the leading edges (refer to point 1 on all figures) of the delay line input and output pulses or between an otherwise designated input and output point.

3.6.4 Pulse Duration (see figures)t

3.6.5 Pulse Fall Time (see figures)t_{fn}

3.6.6 Pulse Rise Time (see figures)t_{rn}

3.7 Voltage Attenuationα

The difference in voltage amplitude between delay line input and output pulses or between an otherwise designated input (E_{in}) and output (E_{no}). Expressed in % or db as:

$$3.7.1 \alpha(\%) = \frac{E_i - E_o}{E_i} \times 100 \text{}(\%)$$

$$3.7.2 \alpha(\text{db}) = 20 \log_{10} \frac{E_i}{E_o} \text{}(\text{db})$$

$$3.7.3 = 20 \log_{10} \frac{E_{ni}}{E_{no}} \text{}(\text{db})$$

4. NOTES

4.1 Figure 1 — General case.

4.2 Figure 2 — Where tilt is essentially 0 (zero), the axis of oscillation will be horizontal, eliminating the need of establishing intersection points 2 and 3 of Figure 1.

4.3 Figure 3 — Where pulse width is narrowed to the point where no axis of oscillation (A_p) can be established then the pulse amplitude (E) will be considered as the peak of the pulse.

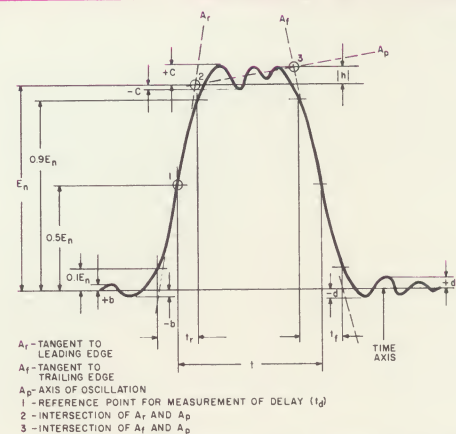


Figure 1 GENERAL CASE

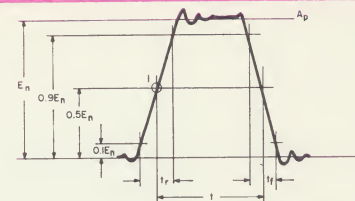


Figure 2 SPECIAL CASE I

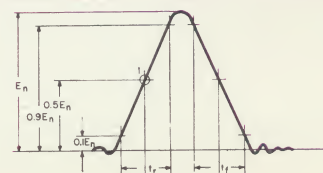


Figure 3 SPECIAL CASE II

STANDARD LUMPED — PARAMETER DELAY LINES

Delay Tolerance: $\pm 5\%$

Attenuation:

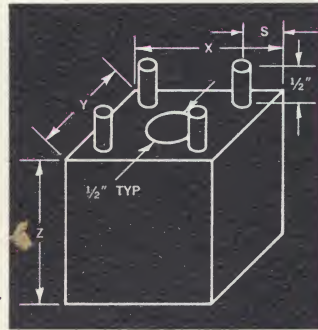
1 μsec and below: 1 db max.
1 μsec — 10 μsec : 3 db max.
10 μsec — 25 μsec : 5 db max.

Temperature Coefficient of Delay:
50 ppm /°C. max.

Operating Temperature Range:
-55°C. to 125°C.

Construction: Hermetically sealed in
steel case

Finish: Grey lacquer over hot tin dip or
copperplate



Case Letter	X	Y	Z	S	# Studs	Stud Thread
A	1 1/2"	1 1/2"	3"	1/4"	2	6-32
B	2"	2"	4"	1/4"	4	6-32
C	2"	4"	4"	3/8"	4	8-32
D	4"	4"	4"	3/8"	4	8-32

LFE MODEL NUMBER					
DELAY TIME	RISE TIME	CHARACTERISTIC IMPEDANCE			
		50 Ω	100 Ω	500 Ω	1000 Ω
.25 μsec	.015 μsec	0050-0.25-.015A	0100-0.25-.015A	0500-0.25-.015A	1000-0.25-.015A
	.025 μsec	0050-0.25-.025A	0100-0.25-.025A	0500-0.25-.025A	1000-0.25-.025A
.50 μsec	.03 μsec	0050-0.50-.03A	0100-0.50-.03A	0500-0.50-.03A	1000-0.50-.03A
	.05 μsec	0050-0.50-.05A	0100-0.50-.05A	0500-0.50-.05A	1000-0.50-.05A
1.0 μsec	.03 μsec	0050-1.00-.03B	0100-1.00-.03B	0500-1.00-.03B	1000-1.00-.03B
	.05 μsec	0050-1.00-.05A	0100-1.00-.05A	0500-1.00-.05A	1000-1.00-.05A
	.10 μsec	0050-1.00-.10A	0100-1.00-.10A	0500-1.00-.10A	1000-1.00-.10A
5.0 μsec	.15 μsec	0050-5.00-.15C	0100-5.00-.15C	0500-5.00-.15C	1000-5.00-.15C
	.25 μsec	0050-5.00-.25B	0100-5.00-.25B	0500-5.00-.25B	1000-5.00-.25B
	.50 μsec	0050-5.00-.50A	0100-5.00-.50A	0500-5.00-.50A	1000-5.00-.50A
10.0 μsec	.30 μsec	0050-10.0-.30C	0100-10.0-.30C	0500-10.0-.30C	1000-10.0-.30C
	.50 μsec	0050-10.0-.50C	0100-10.0-.50C	0500-10.0-.50C	1000-10.0-.50C
	1.0 μsec	0050-10.0-1.00B	0100-10.0-1.00B	0500-10.0-1.00B	1000-10.0-1.00B
25.0 μsec	.5 μsec	0050-25.0-.50D	0100-25.0-.50D	0500-25.0-.50D	1000-25.0-.50D
	1.0 μsec	0050-25.0-1.00C	0100-25.0-1.00C	0500-25.0-1.00C	1000-25.0-1.00C
	2.5 μsec	0050-25.0-2.50B	0100-25.0-2.50B	0500-25.0-2.50B	1000-25.0-2.50B

Letters following model numbers refer to case sizes as given in table above

STANDARD DISTRIBUTED — PARAMETER DELAY LINES

Delay Tolerance: $\pm 5\%$

Attenuation: 1 db/ μsec (approx.)

Temperature Coefficient of Delay: 70 PPM/°C. max.

Operating Temperature Range: -55°C. to +125°C.

Construction: Epoxy-encapsulated in 3/8" O.D. epoxy or
phenolic tube; pigtail leads 6" long

Length: up to 0.3 μsec — 2"
0.3 μsec to 0.5 μsec — 4"
0.5 μsec to 1 μsec — 6"

LFE MODEL NUMBER					
DELAY TIME	RISE TIME	CHARACTERISTIC IMPEDANCE			
		500 Ω	1000 Ω	1500 Ω	2000 Ω
.05 μsec	.01 μsec	0500-0.05DP	1000-0.05DP	1500-0.05DP	2000-0.05DP
.10 μsec	.015 μsec	0500-0.10DP	1000-0.10DP	1500-0.10DP	2000-0.10DP
.20 μsec	.03 μsec	0500-0.20DP	1000-0.20DP	1500-0.20DP	2000-0.20DP
.30 μsec	.04 μsec	0500-0.30DP	1000-0.30DP	1500-0.30DP	2000-0.30DP
.40 μsec	.06 μsec	0500-0.40DP	1000-0.40DP	1500-0.40DP	2000-0.40DP
.50 μsec	.07 μsec	0500-0.50DP	1000-0.50DP	1500-0.50DP	2000-0.50DP
.60 μsec	.08 μsec	0500-0.60DP	1000-0.60DP	1500-0.60DP	2000-0.60DP
.70 μsec	.10 μsec	0500-0.70DP	1000-0.70DP	1500-0.70DP	2000-0.70DP
.80 μsec	.12 μsec	0500-0.80DP	1000-0.80DP	1500-0.80DP	2000-0.80DP
.90 μsec	.13 μsec	0500-0.90DP	1000-0.90DP	1500-0.90DP	2000-0.90DP
1.00 μsec	.14 μsec	0500-1.00DP	1000-1.00DP	1500-1.00DP	2000-1.00DP

The delay lines on this list are intended to meet the majority of prototype requirements with fast delivery and at low cost. However, they do not represent the limits of the state-of-the-art, nor are they intended as substitutes for custom networks designed to specific requirements.

MEASUREMENTS

A basic pulse delay line measurement set-up is shown in Figure 4. The delay is measured by counting the number of time markers between input and output signals; these time markers may be fed either into one of the vertical amplifiers or into the Z-axis modulation terminals of the oscilloscope. The output rise time of the pulse generator should be no more than 1/10 of the delay line rise time; the bandwidth of the oscilloscope should be at least five times that of the delay line. Low capacity probes should be used to reduce loading of the network.

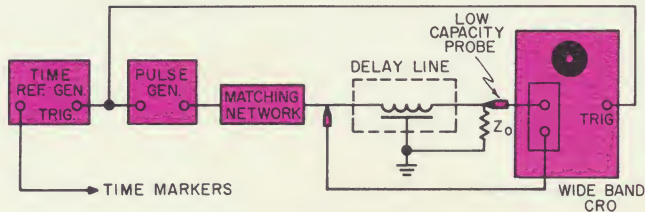


Figure 4.

APPLICATIONS

Electromagnetic delay lines have found wide application in all fields of electronics — as storage and pulse shaping devices; in auto-correlation and phasing systems; in coincidence and discriminator circuits; in encoders and decoders; etc. The figures shown illustrate some typical applications.

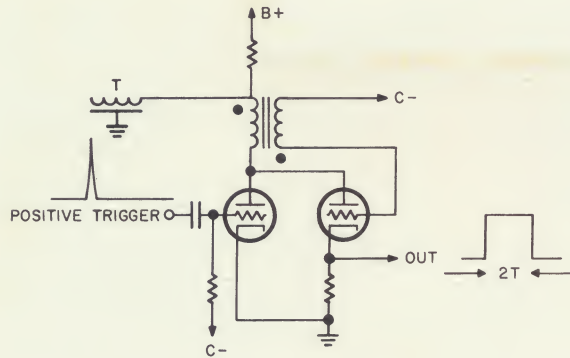


Figure 5. Delay Line-Controlled Blocking Oscillator

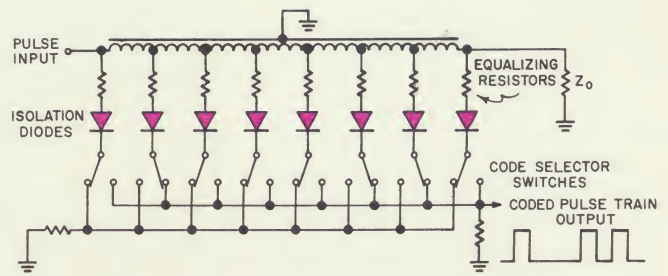


Figure 6. Serial Pulse Position Encoder

SPECIFYING ELECTROMAGNETIC DELAY LINES

Specifications should include the following:

1. Delay and tolerance
2. Maximum output rise time
3. Maximum attenuation
4. Characteristic impedance
5. Maximum allowable distortion
6. Maximum pulse input level
7. Insulation resistance and hipot level
8. Maximum temperature coefficient
9. Physical size; package, terminal, and mounting requirements
10. Environmental requirements

A general description of the application, with schematics of the driving circuitry and illustration of input waveform characteristics, is highly desirable. Consultation with our experienced delay line engineers before a design is frozen will result in great benefits to the buyer with respect to both cost and reliability.

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